TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type (U-MOSIV) ataSheet4U.com

TPCP8202

Portable Equipment Applications

Motor Drive Applications

DC/DC Converters

· Lead (Pb)-free

• Low drain-source ON-resistance: $R_{DS(ON)} = 19 \text{ m}\Omega$ (typ.)

• High forward transfer admittance: |Y_{fs}| = 20 S (typ.)

• Low leakage current: $I_{DSS} = 10 \mu A (max)(V_{DS} = 30 V)$

Enhancement model: V_{th} = 0.7 to 1.4V

 $(V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A})$

Absolute Maximum Ratings (Ta = 25°C)

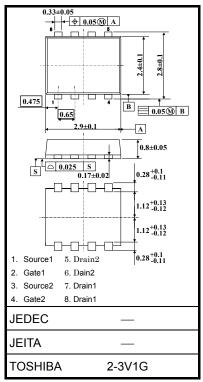
Cha	racteristic	Symbol	Rating	Unit	
Drain-source volta	ge	V_{DSS}	30	V	
Drain-gate voltage	(R _{GS} = 20 kΩ)	V_{DGR}	30	V	
Gate-source voltage	je	V _{GSS}	±12	V	
Drain current	DC (Note 1)	ID	5.5	А	
Drain current	Pulse (Note 1)	I _{DP}	30 30 ±12		
Drain power	Single-device operation (Note 3a)	P _{D (1)}	1.48	W	
dissipation (t = 5 s) (Note 2a)	Single-device value at dual operation (Note 3b)	P _{D (2)}	1.23		
Drain power dissipation (t = 5 s) (Note 2b)	Single-device operation (Note 3a)	P _{D (1)}	0.58		
	Single-device value at dual operation (Note 3b)	P _{D (2)}	0.36		
Single-pulse avala	nche energy (Note 4)	E _{AS}	7.86	mJ	
Avalanche current		I _{AR}	I _{AR} 5.5		
Repetitive avalanc Single-device value		E _{AR}	E _{AR} 0.12		
Channel temperatu	ıre	T _{ch}	150	°C	
Storage temperatu	re range	T _{stg}	–55 to 150 °		

Note: For Notes 1 to 6, see the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

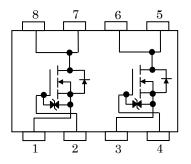
This transistor is an electrostatic-sensitive device. Handle with care.

Unit: mm

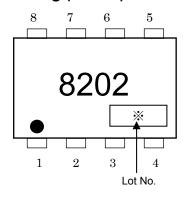


Weight: 0.017 g (typ.)

Circuit Configuration



Marking (Note 6)



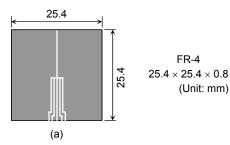
Thermal Characteristics

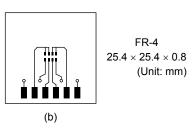
Chara	Symbol	Max	Unit	
Thermal resistance, channel to ambient (t = 5 s) (Note 2a)	Single-device operation (Note 3a) Rth (ch-a) (1)		84.5	°C/W
	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	101.6)
Thermal resistance, channel to ambient	Single-device operation (Note 3a)	R _{th (ch-a) (1)}	215.5	°C/W
(t = 5 s) (Note 2b)	Single-device value at dual operation (Note 3b)	R _{th (ch-a) (2)}	347.2	C/VV

Note 1: Ensure that the channel temperature does not exceed 150°C.

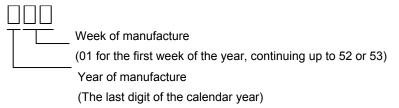
Note 2: (a) Device mounted on a glass-epoxy board (a) (b) [

(b) Device mounted on a glass-epoxy board (b)





- Note 3: a) The power dissipation and thermal resistance values shown are for a single device. (During single-device operation, power is applied to one device only.)
 - b) The power dissipation and thermal resistance values shown are for a single device. (During dual operation, power is applied to both devices evenly.).
- Note 4: $V_{DD} = 24$ V, $T_{ch} = 25$ °C (initial), L = 0.2 mH, $R_G = 25$ Ω , $I_{AR} = 5.5$ A
- Note 5: Repetitive rating: Pulse width limited by Max. Channel temperature.
- Note 6: on the lower left of the marking indicates Pin 1.
 - * Weekly code (3 digits):





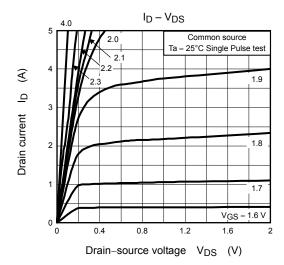
Electrical Characteristics (Ta = 25°C)

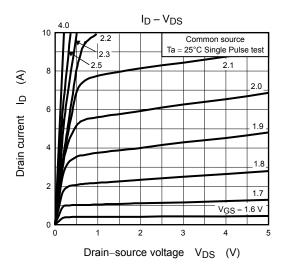
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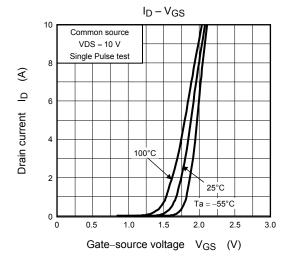
Cha	aracteristic	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cur	rent	I _{GSS}	$V_{GS} = \pm 10 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±10	μА	
Drain cutoff curre	ent	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V	_	_	10	μА	
Drain source breakdown voltage		V _{(BR)DSS}	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	30	_	_	V	
Diam-30dice bic	rain-source breakdown voltage		$I_D = 10 \text{ mA}, V_{GS} = -12 \text{ V}$	15	_	_	v	
Gate threshold vo	oltage	V _{th}	$V_{DS} = 10 \text{ V}, I_D = 200 \mu\text{A}$	0.7	_	1.4	V	
		R _{DS} (ON)	$V_{GS} = 2.5 \text{ V}, I_D = 2.8 \text{ A}$		29	39	mΩ	
Drain-source ON	-resistance	R _{DS} (ON)	$V_{GS} = 4.0 \text{ V}, I_D = 2.8 \text{A}$	_	20	24		
		R _{DS} (ON)	$V_{GS} = 4.5 \text{ V}, I_D = 2.8 \text{A}$	_	19	23		
Forward transfer admittance		Y _{fs}	$V_{DS} = 10 \text{ V}, I_D = 2.8 \text{A}$	10	20	_	S	
Input capacitance		C _{iss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	2150	_	pF	
Reverse transfer capacitance		C _{rss}		_	155	_		
Output capacitance		Coss			165	_		
Reverse transfer of	Rise time	t _r	V _{DD} ≈ 15 ∨ V _{DD}		10	_		
	Turn-on time	t _{on}		_	20	_	ns	
	Fall time	t _f		_	19	_		
	Turn-off time	t _{off}	Duty ≦ 1%, t _W = 10 μs	_	90	_		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq 24 \text{ V, V}_{GS} = 10 \text{ V,}$ $I_D = 5.5 \text{ A}$	_	28	_	nC	
Gate-source charge1		Q _{gs1}		_	4	_		
Gate-drain ("Miller") charge		Q _{gd}		_	8	_		

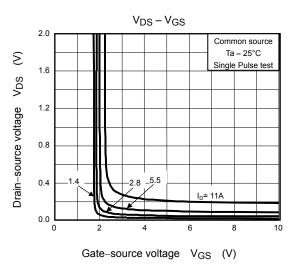
Source-Drain Ratings and Characteristics (Ta = 25°C)

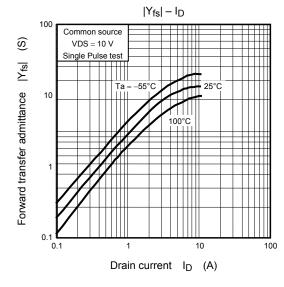
Characteristic		Symbol	Test Condition	Min	Тур.	Max	Unit
Drain reverse current	Pulse (Note 1)	I _{DRP}	_	_	_	22	Α
Forward voltage (diode)		V_{DSF}	IDR = 5.5 A, $VGS = 0 V$			-1.2	V

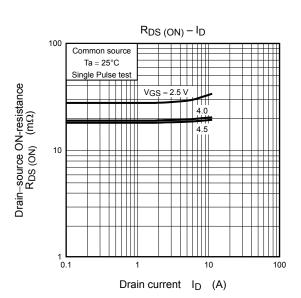




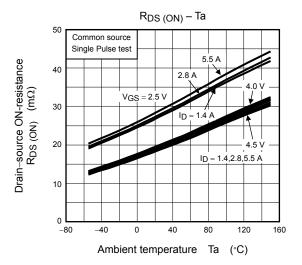


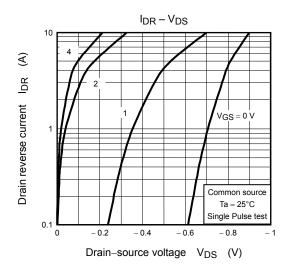


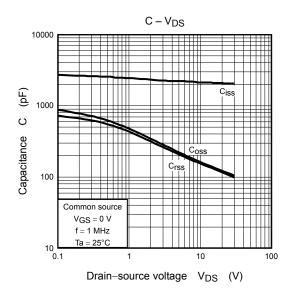


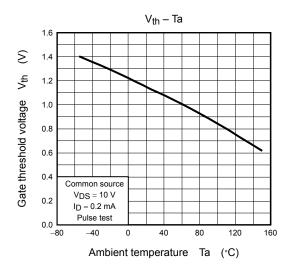


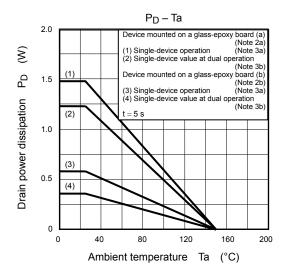
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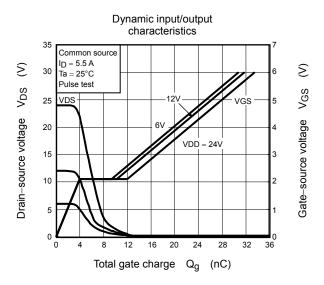


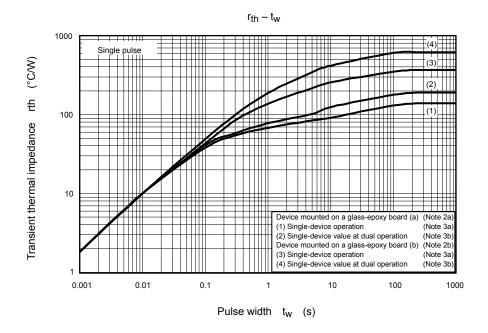


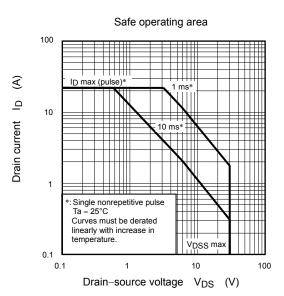












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